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Amendment to Test Report

This Amendment is valid only together with the main Test Report

Report No: 270272

Main Report No: 246038

Date of issue: September 23, 2014

Total number of pages: 6

Applicant's Name: Power Integrations, Inc.

Address: 5245 Hellyer Avenue, San Jose, CA 95138, U.S.A.

Test specification

Standard: IEC 60950-1:2005 (Second Edition) + Am 1:2009 + Am 2:2013 with

CTL Decision, DSH 1080

Test procedure: CB scheme

Non-standard test method: N/A

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This report is not valid as a CB Test Report unless signed by an approved CB Testing Laboratory and appended to a CB Test Certificate issued by an NCB in accordance with IECEE 02.

Test item description: IC including capacitor discharge function (ICX)

Trade Mark: CAPZero

Manufacturer: Power Integrations, Inc.

Model/Type reference: CAP002DG; CAP003DG; CAP004DG; CAP005DG; CAP006DG;

CAP007DG; CAP008DG; CAP009DG; CAP012DG; CAP013DG; CAP014DG; CAP015DG; CAP016DG; CAP017DG; CAP018DG;

CAP019DG; SC1143

Ratings.....: 230V AC nominal (tested for 85-265V AC, 47-63Hz)

Nemko Rev. 2013-10



Report No. 270272



Testing procedure and testing location:			
	Nemko A/S		
Testing location/ address:	Gaustadalléen 30, NO - 0373 Oslo, Norway		
☐ Associated CB Laboratory:			
Testing location/ address:			
Tested by (name + signature)	: Ole Morten Aaslund	Ole Morker assund	
Approved by (name + signature)		Harle	
☐ Testing procedure: TMP			
Testing location/ address:			
Tested by (name + signature)	:		
Approved by (name + signature)	:		
☐ Testing procedure: WMT			
Testing location/ address:			
Tested by (name + signature)	:		
Witnessed by (name + signature).	:		
Approved by (name + signature)	:		
☐ Testing procedure: SMT			
Testing location/ address:			
Tested by (name + signature)	:		
Approved by (name + signature)	:		
Supervised by (name + signature)	:		
☐ Testing procedure: RMT			
Testing location/ address:			
Tested by (name + signature)	:		
Approved by (name + signature)	:		
Supervised by (name + signature)			





Photos (2 pages)

Summary of testing:

The following additional tests were performed as per *DSH 1080* due to the introduction of different minimum and maximum X-capacitance and resistance values:

- 100 positive impulses and 100 negative impulses between line and neutral using a capacitor with the largest capacitance and a resistor with the smallest resistance specified by the manufacturer of the ICX; and repeated with a capacitor with the smallest capacitance and the resistor with the largest resistance. The time between any two impulses shall not be less than 1 s. The impulse shall be as specified in circuit 2 of Table N.1 (60950-1) / 1.2/50µs in Table K.1 (60065), with Uc equal to the transient voltage.

Impulse tests as described performed on models CAP002DG, CAP009DG, CAP012DG and CAP019DG. Uc = 2500Vpeak.

- 10 000 cycles of power on and off using a capacitor with the smallest capacitance and a resistor with the largest resistance as specified by the manufacturer of ICX. The power on and off cycles time shall not be less than 1 s.

10 000 cycles of power on and off (cycle time is 1 s) performed on models CAP002DG and CAP012DG.

After above additional tests the capacitor discharge tests were performed according to clause 2.1.1.7 on models CAP002DG, CAP009DG, CAP012DG and CAP019DG. The circuit tested continue to comply with 2.1.1.7, refer 2.1.1.7 for details. Note that compliance with 2.1.1.7 must also be checked when the ICX forms part of an end product.

Tests performed (name of test and test clause):	Testing location:
2.1.1.7 Discharge of capacitors in equipment	Nemko A/S Gaustadalléen 30, NO-0373 Oslo, Norway

Summary of compliance with National Differences

Samples tested comply with the applicable requirements covered by CTL Decision, DSH 1080.

Copy of marking plate

The artwork below may be only a draft. The use of certification marks on a product must be authorized by the respective NCBs that own these marks.

Refer main report.



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Calibration	All instruments used in the f	sasta given in this test report are calibrated and	
Cambration	All instruments used in the tests given in this test report are calibrated and traceable to national or international standards.		
	Further information about traceability will be given on request.		
Measurement	Measurement uncertainties are calculated for all instruments and instrument		
uncertainty	set-ups given in this report. Calculations are based on the principles given in		
	the standard EA-4/02 (Dec. 1999), IEC Guide 115:2007 and other relevant internal Nemko-procedures.		
	Further information about measurement uncertainties will be given on request.		
Evaluation of results	If not explicitly stated othery	vise in the standard, the test is passed if the	
		or below (above) the limit line, regardless of the	
		f the measured value is above (below) the limit line,	
		EC Guide 115:2007. The instrumentation accuracy is	
	within limits agreed by IECE	E-CIL.	
Danaikla tart			
Possible test case verd			
- test case does not app	ly to the test object:	Not Applicable (N/A)	
- test object does meet t	the requirement:	Pass (P)	
- test object does not me	eet the requirement::	Fail (F)	
Testing	:		
Date of receipt of test item: September 17, 2014			
Date(s) of performance of tests: September 17 – September 23, 2014			
General remarks:			
	d in this report relate only to the		
This report shall not be reproduced, except in full, without the written approval of the Issuing testing laboratory.			
"(see Enclosure #)" refers to additional information appended to the report.			
"(see appended table)" refers to a table appended to the report.			
Throughout this report	a □ comma / ⊠ point is us	sed as the decimal separator.	
Manufacturer's Declara	ation per sub-clause 6.2.5 o	f IECEE 02:	
The application for obtaining	•	☐ Yes	
Certificate includes mo			
	ion from the Manufacturer	Not applicable ■	
stating that the sample			
` , .	esentative of the products		
from each factory has I	been provided:		

Pudong New Area, Shanghai, 201203 CHINA	Name and address of factory (ies): Millenium Microtech Shanghai No. 351 Guo Shou Jing Rd., Z.J. Hi Tech Park
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When differences exist; they shall be identified in the General product information section.



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General product information:

The update concerned in this amendment report covers the introduction of different minimum and maximum X-capacitance and resistance values as follows:

X-capacitance: Min. 100nF, max. $6\mu F$ Resistance: Min. $142k\Omega$, max. $7.5M\Omega$

In addition it covers update to included Amd 2:2013 of IEC 60950-1(ed2).

Models covered by this amendment report are listed in table below. Models CAP002DG, CAP009DG, CAP012DG and CAP019DG were chosen to represent all models. During testing the ICX was mounted on a PCB together with a mains fuse (1A), X-capacitor and discharge resistors, refer attached photos. Values of X-capacitor and discharge resistors are as per recommendation from the manufacturer. Refer table below

Model/Part No. (ICX)	BV _{DSS}	Total X-capacitance - range	Total series resistance - range (R1+R2)
CAP002DG	825V	100nF-600nF	7.5ΜΩ–1.42ΜΩ
CAP003DG	825V	100nF-900nF	7.5MΩ–970kΩ
CAP004DG	825V	100nF–1.2μF	7.5MΩ–740kΩ
CAP005DG	825V	100nF–1.8µF	7.5MΩ–456kΩ
CAP006DG	825V	100nF–2.4µF	7.5MΩ–342kΩ
CAP007DG	825V	100nF–3.0μF	7.5MΩ–285kΩ
CAP008DG	825V	100nF–4.2μF	7.5MΩ–190kΩ
CAP009DG	825V	100nF–6μF	7.5MΩ–142kΩ
CAP012DG	1000V	100nF-600nF	7.5ΜΩ–1.42ΜΩ
CAP013DG	1000V	100nF-900nF	7.5MΩ–970kΩ
CAP014DG	1000V	100nF 1.2μF	7.5MΩ–740kΩ
CAP015DG	1000V	100nF–1.8μF	7.5MΩ–456kΩ
CAP016DG	1000V	100nF-2.4µF	7.5MΩ–342kΩ
CAP017DG	1000V	100nF–3.0μF	7.5MΩ–285kΩ
CAP018DG	1000V	100nF–4.2μF	7.5MΩ–190kΩ
CAP019DG	1000V	100nF–6µF	7.5MΩ–142kΩ
SC1143	1000V	100nF–6μF	7.5MΩ–142kΩ





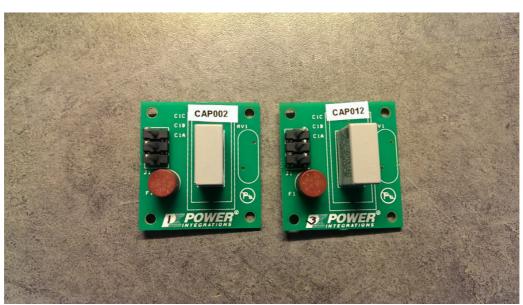
Project history	:	
Nemko Report/ Order No.:	Modification to the appliances:	Changes/ Modifications in clause(s):
246038	Main Test Report	N/A
247613	Adding of voltage and frequency range; 85-265V AC, 47-63Hz. Note that DSH 1080 only covers Installation Category II (2.5kV transients), and end products using the ICX covered by this report must follow the same Installation Category.	Summary of testing, Test items particulars, General product information, 2.1.1.7
270272	Introduction of different minimum and maximum X-capacitance and resistance values: X-capacitance: Min. 100nF, max. 6μF Resistance: Min. 142kΩ, max. 7.5MΩ Refer also General product information. Upgrade to include Amd 2:2013 of IEC 60950-1(ed2).	Summary of testing, General product information, 2.1.1.7

2.1.1.7	Discharge of capacitors in equipment	Capacitor discharge tests performed on models CAP002DG, CAP009DG, CAP012DG and CAP019DG after tests described in Summary of testing were perfomed. Refer test results below. Discharge tests must also be performed when the ICX forms part of an end product.	Р
	Measured voltage (V); time-constant (s):	CAP002DG: Vpeak: 358V Vpeak, 37%: 132.5V Time-constant: 745ms CAP009DG: Vpeak: 352V Vpeak, 37%: 130.2 V Time-constant: 829ms CAP012DG: Vpeak: 356V Vpeak, 37%: 131.7V Time-constant: 738ms CAP019DG: Vpeak: 355V Vpeak, 37%: 131.4V Time-constant: 844ms	



Photos

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Test board of CAP002DG and CAP012DG

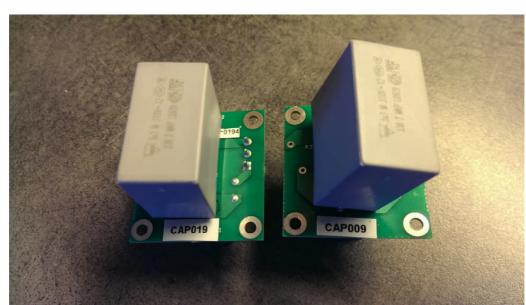


Test board of CAP002DG and CAP012DG

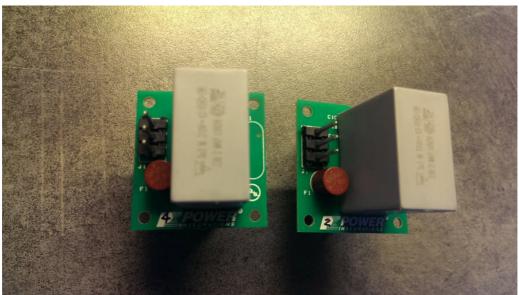


Photos

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Test board of CAP009DG and CAP019DG



Test board of CAP009DG and CAP019DG